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PATENT APPLICATION

Examiner: NYA

Group Art Unit: NYA

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July 28, 2005

INFORMATION DISCLOSURE STATEMENT

For the concise explanation of relevance for non-English document 8-96703, the Examiner is respectfully referred to the English Abstract attached thereto and to counterpart U.S. Patents 5,939,823 and 5,989,404.


For the concise explanation of relevance for non-English document 2001-6523, the Examiner is respectfully referred to the English Abstract attached thereto and to counterpart U.S. Patent 6,861,790.

For the concise explanation of relevance for non-English document 2001-101966, the Examiner is respectfully referred to the English Abstract attached thereto and to counterpart U.S. Patent 6,650,061.

It is respectfully requested that the above information be considered by the Examiner and that a copy of the enclosed Form PTO-1449 be returned indicating that such information has been considered.

Applicants' undersigned attorney may be reached in our New York office by telephone at (212) 218-2100. All correspondence should continue to be directed to our address given below.

Respectfully submitted,



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FORM PTO 1449 (modified) U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE LIST OF REFERENCES CITED BY APPLICANT(S) (Use several sheets if necessary)				ATTY DOCKET NO. 03500.017320.		APPLICATION NO. 10/516,545	
Date Submitted to PTO: [DATE]				APPLICANT TAKESHI ICHIKAWA ET AL.		FILING DATE DECEMBER 2, 2004	
U.S. PATENT DOCUMENTS				GROUP NYA			
*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE	
	4,663,559	5/87	Christensen	313	336		
	5,939,823	8/99	Kiyomiya et al.	313	495		
	5,989,404	11/99	Kiyomiya et al.	205	96		
	6,288,494	9/01	Tsukamoto et al.	315	169.1		
	6,583,582	6/03	Ichikawa	315	169.3		
	6,583,553	6/03	Sasaguri	313	495		
	6,650,061	11/03	Urayama et al.	315	169.3		
	6,683,408	1/04	Ichikawa	313	495		
	2004/0251812 A1	12/04	Fujiwara et al.	313	495		
	6,861,790	3/05	Iwasa et al.	313	346		
FOREIGN PATENT DOCUMENTS							
	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES/NO/ OR ABSTRACT	
	8-96703	4/96	Japan			Abstract	
	2001-6523	1/01	Japan			Abstract	
	2001-101966	4/01	Japan			Abstract	
	4-131846	5/92	Japan			Abstract	
	8-96704	4/96	Japan			Abstract	
	8-264109	10/96	Japan			Abstract	
	2001-202870	7/01	Japan			Abstract	
OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)							
	Forest, R.D., et al., A Study of Electron Field Emission as a function of film thickness from amorphous Carbon Films, Applied Physics Letters, Vol. 73, No. 25, pp 3784-3786 (1998)						
EXAMINER			DATE CONSIDERED				

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

